

Key Points Summary

Rowland, J. A., Martindale, S. L., Spengler, K. M., Shura, R. D., & Taber, K. H. (2020). Sequelae of blast events in Iraq and Afghanistan War veterans using the Salisbury Blast Interview: A CENC study. Brain Injury, 34(5), 642-652. doi:10.1080/02699052.2020.1729418

Primary Question this Study Addresses

How is blast exposure comprehensively characterized across the lifespan of post-deployment Veterans and service members when using the Salisbury Blast Interview (SBI), and what is the relationship to traumatic brain injury (TBI)?

Study Findings That Add to Our Knowledge

Based on the SBI, over 94% of participants reported at least one blast event, and approximately 20% reported experiencing a TBI during a blast event.

Subjective ratings of blast characteristics were higher when TBI was experienced, and lower when behind cover.

Pressure had the strongest association with resulting TBI. Pressure, temperature and distance were the best predictors of TBI, and pressure was the best predictor of primary blast TBI.

How Study Evidence Might Be Used in Practice

The blast characteristics most associated with resulting TBI were pressure, temperature, and distance. Pressure was the best predictor of primary blast TBI.

The SBI method comprehensively characterized blast events, particularly in military populations, and may be useful to treating clinicians.

For more information on blast injury and TBI, please visit:



To access the study abstract, click here:



Abstract

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